

Development of silicon detectors for Beam Loss Monitoring at HL-LHC

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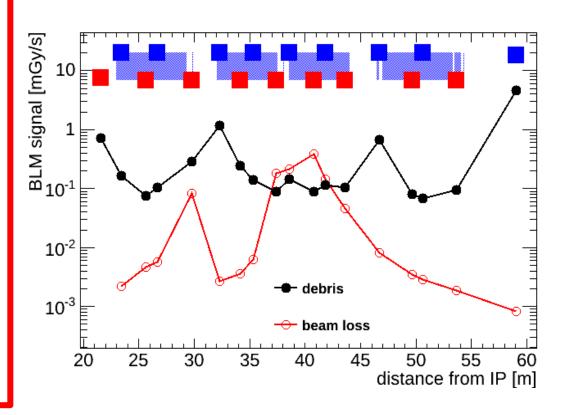
Motivation and background

Low beam losses – regular regime for LHC operation.
Increased beam loss -

fast pressure increase, particles of dust inside the beam pipe, etc.

• Energy deposition from beam loss might heat up LHe magnets and then:

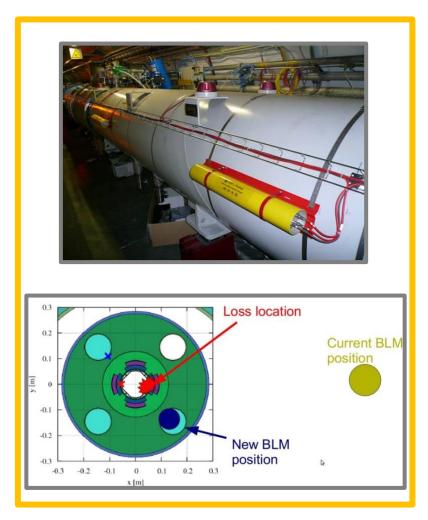
Beam losses must be carefully monitored



Solution: Place BLM sensor close to the magnet coil or integrate it in the coil construction. This requires:

- Operational temperature 1.9 4K
- No access along the magnet lifetime
- Irradiation by debris up to fluence of 10e¹⁶ p/cm²

Silicon BLM concept



Operational conditions:

- 1. Operational temperature 1.9 4K
- 2. No access along the magnet lifetime
- Irradiation by debris up to fluence of 10e¹⁶ p/cm²

Technical requirements

- 1. Compactness
- 2. Technology of mass-production
- 3. Reproducibility of characteristics
- 4. Cost effectiveness

Goal of development

- 1. Full prototype of BLM
- 2. Predictable scenario of degradation

Development under collaboration:

Be-Bi-BL group, RD39 (CERN), loffe institute (St. Petersburg), HIP (Helsinki)

Expected problems

- Complicate irradiation test: *irradiation in super-flued He 1.9K or liquid He 4.3K each experiment requires individual cryostat*
 Limited experimental technique:
 - TSC, DLTS, I(T), C(V) methods are not available
- 3. Precise alignment of invisible beam with invisible set of samples
- 3. Non stop data collection for ~ 1 month
- 4. Not enough data on:
 - Radiation induced defects formation
 - Properties of radiation induced defects as a trapping centers at at LHe
 - Simulation tools

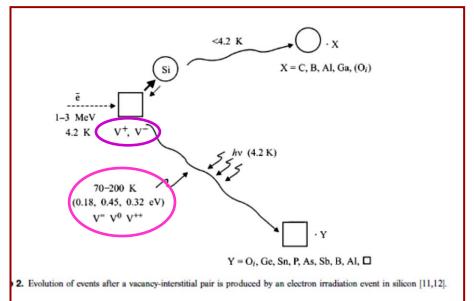
Solution

Application of laser based TCT and CCE vs. V and F analysis

Radiation damage in Si at cryogenic T

Available:

 renewed wide knowledge on radiation damage of Si detectors at RT and slight cooling (down to -50°C) – CERN RD collaborations, experiments at LHC



- G. D. Watkins, EPR of Defects in Semiconductors: Past, Present, Future, Phys. of Solid State, 41 (1999) 746-750.
- G. D. Watkins, Defects and diffusion in silicon processing, Ed. T. D. De la Rubia, et al.; MRS Sypm. Proc. Vol. 469, Pittsburgh (1997) 139.

Low T: <u>raw</u> bulk silicon

Interstitials – mobile at T~4K Vacancies (V+, V-) - mobile at: T~70K (standard n-Si) T~150K (standard p-Si) T~ 200K (high resistivity Si)

Expected radiation damage at LHe T: formation of vacancy-related defects critical for degradation <u>is suggested to</u> <u>be suppressed</u>

Milestones and timelines of cryoBLM development

- 2012 first test of as-processed Si PIN detector operation at 4 K: proof of concept , measurements of transport properties
- 2012 *in situ* RadTest 1 at 1.9K: standard detectors (300 μm)
- 2014 *in situ* RadTest 2 at 1.9 K: first study of thin BLM (100 μm)
- 2014 installation of the first Si BLM modules 2015 – *in situ* <u>RadTest 3</u> at 4.1 K: Improved design of thin BLM statistics of degradation scenario

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In situ RadTests 1:

 P+/n/n+ silicon pad detectors designed and processed by consortium of the loffe Institute, St.
 Petersburg, and Research Institute of Material Science and Technology, Zelenograd, both Russia

ρ: <u>10-15 kΩcm (mostly)</u>, 500 Ωcm and 4.5 Ωcm; thickness *W*: 300 μm

• Detector operation at reverse and forward bias mode;

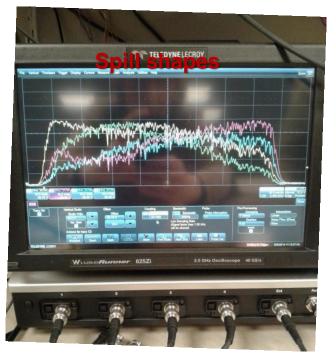
forward – Current Injected Detectors (CID)

Measurements

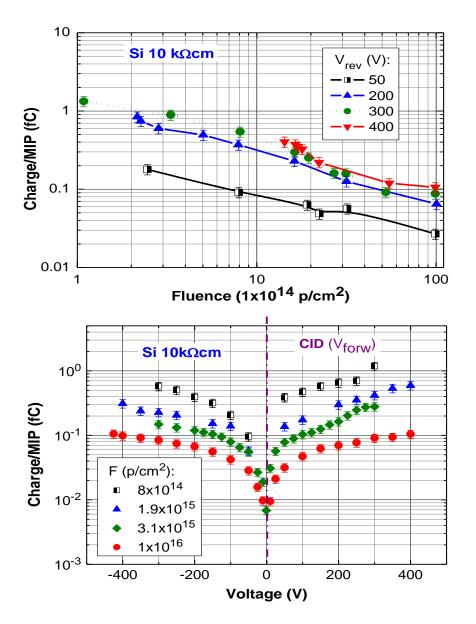
 Collected charge Q_c: determined by integrating the detector output current over the 400 ms spill and averaging over a sequence of spills

♦ TCT : LeCroy, 3 GHz bandwidth, 630 nm laser, width 45 ps (<u>1st test</u>)





RadTest 1 collected charge vs. F and V



300 μm

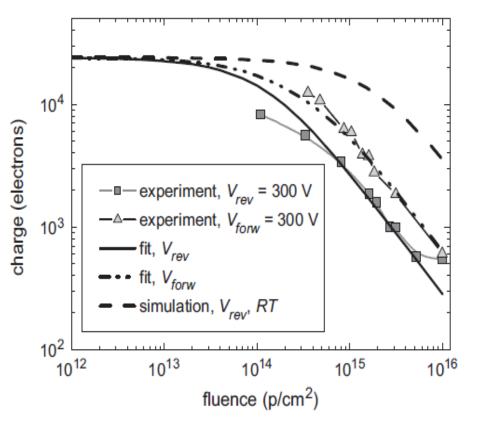
Different silicon resistivity $\rho = 10 \text{ k}\Omega \text{cm}$, 500 and 4.5 Ωcm

All detectors survived irradiation up to 10¹⁶ p/cm² \rightarrow no sensitivity to ρ at this F

Unexpected result – degradation rate higher than at RT

CCE(F) fit with Hecht equation

$$Q_{c} = e\left\{\frac{v_{e}\tau_{e}}{w}\left[1 - \frac{v_{e}\tau_{e}}{w}\left(1 - \exp\left(-\frac{v_{e}\tau_{e}}{w}\right)\right)\right]\right\} + \left\{\frac{v_{h}\tau_{h}}{w}\left[1 - \frac{v_{h}\tau_{h}}{w}\left(1 - \exp\left(-\frac{v_{h}\tau_{h}}{w}\right)\right)\right]\right\}$$



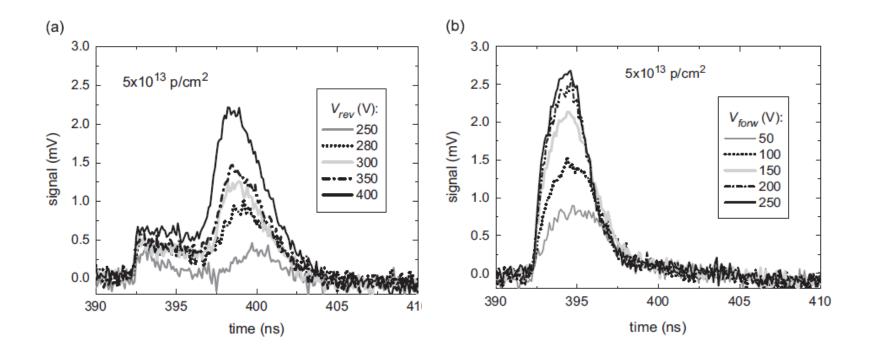
- 1-D approach, E = V/w,
- 2 levels (EVL) model,
- $1/t_{e,h} = b_{e,h}F_{eq}$; b trapping probability constant,
- Drift velocities at 4 K (F = 0): $v_{es} = 1.2x10^7$ cm/s, $v_{hs} = 7x10^6$ cm/s

CCE degradation at LHe can be explained by trapping

Т	1.9 K	RT
$\beta_e (\mathrm{cm}^2\mathrm{ns}^{-1})$	6×10^{-15}	3.2×10^{-16}
$\beta_h (\mathrm{cm}^2 \mathrm{ns}^{-1})$	9×10 ⁻¹⁵	3.5×10^{-16}

 β is up to 25 times larger at 1.9K

TCT voltage scans at 1.9 K

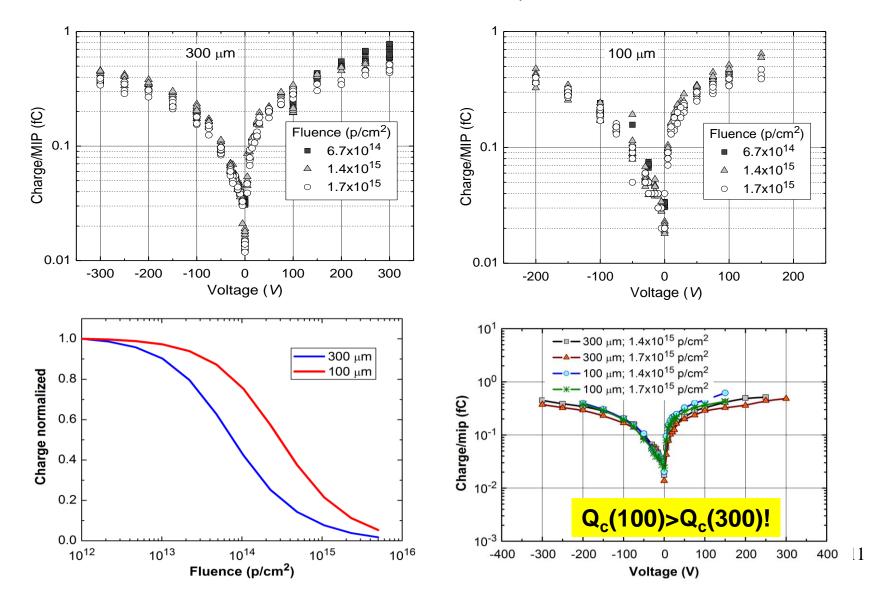


Observation of acceptors domination and DP E(x)

RadTest 2: collected charge vs. F and V

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Test 2; 300 and 100 μm



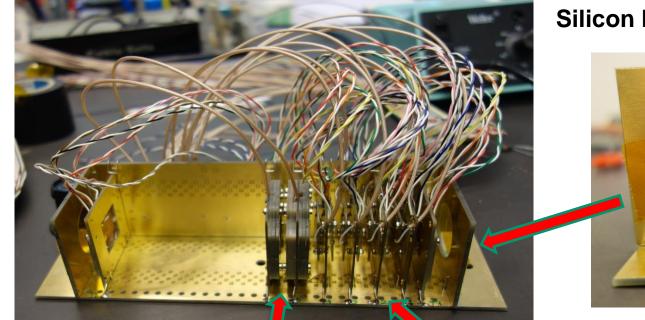
Detectors (modules) for RadTest 3

module	Amount in module	r (kWcm)	d (mm)	area (mm²)	bias (V)	purpose	readout
TeleIN	4	≥15	300	12×12	200	telescope "IN"	oscilloscope
MM1	4	≥15	300	5×5	400	statistics	Ioffe-DAQ
MM2	4	~0.5	300	5×5	500	statistics	_``_
MM3	4	≥15	(100)	5×5	500	statistics	-
MM4	4	≥15	100	5×5	400	statistics	-"-
Ref1	1	≥15	300	5×5	400	test of DAQ system	CERN-DAQ
Ref2	1	≥15	300	5×5	400	-"-	-''-
TeleOUT	4	≥15	300	12×12	200	telescope "OUT"	oscilloscope

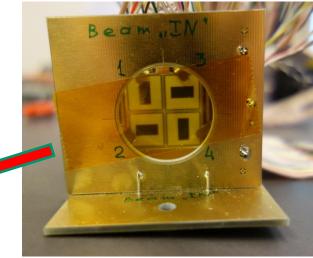
Total detector amount – 26 pcs.

TeleIN and TeleOUT – silicon beam telescopes

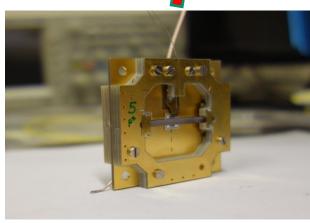
Cassette with detectors modules



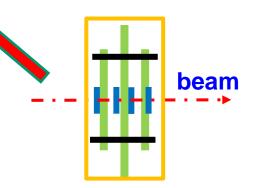
Silicon Beam Telescope module



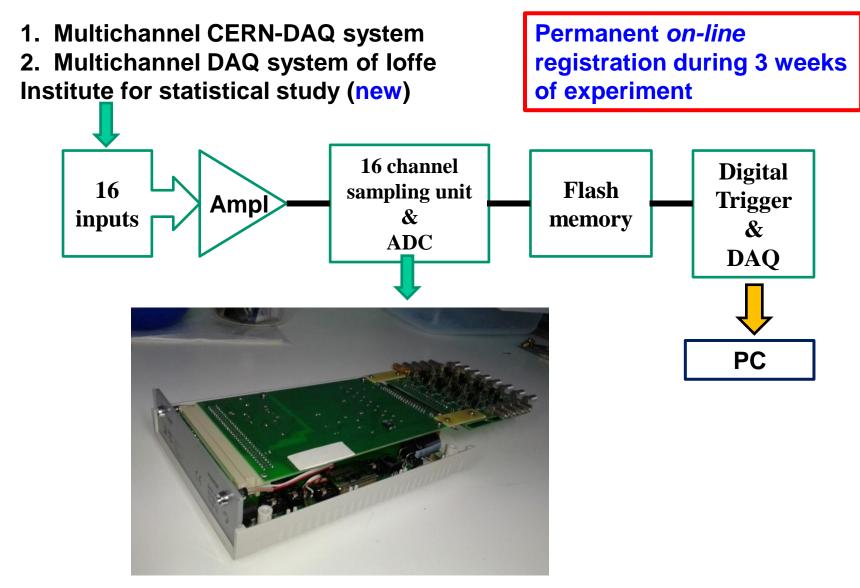
TCT modules (Ref1,2)



Multi-module construction



Electronics

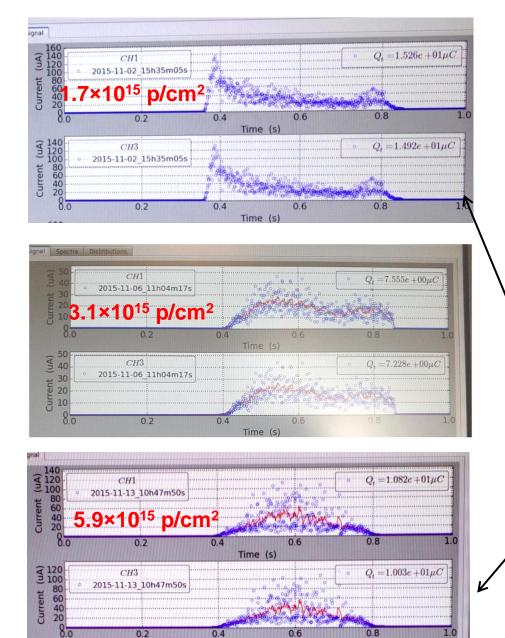


Cryostat for RadTests 3

- Cryogenic system for cooling to 1.9K
- Irradiation at CERN PS
- 23 GeV protons, beam diameter ~1 cm at the detector location
- Beam intensity 1.3×10¹¹
 p/cm²
- per 400 ms spill (~10¹⁰ p/s on detectors)
- Fluence to 2×10¹⁵-1×10¹⁶ p/cm²
- Beam position monitoring







Time (s)

Detector signals from spills at F ~ 10¹⁵ p/cm²

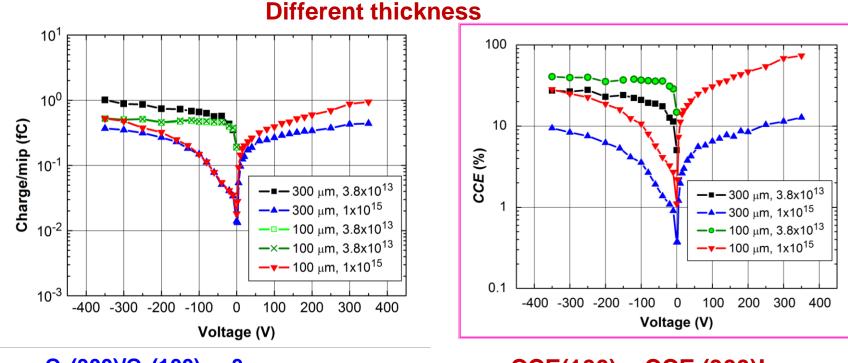
> Spill: Duration - 400 ms Intensity ~ (6-7)×10¹⁰ p/cm²

Data from CERN-DAQ system Detectors: Ref1 (Ch1), Ref2 (Ch3) d = 300 μm

Origin of signal fluctuations is not clear yet.

 This feature is recorded by both DAQ systems.

RadTest 3: CCE in voltage scans



 $Q_o(300)/Q_o(100) = 3$

CCE(100) > CCE (300)!

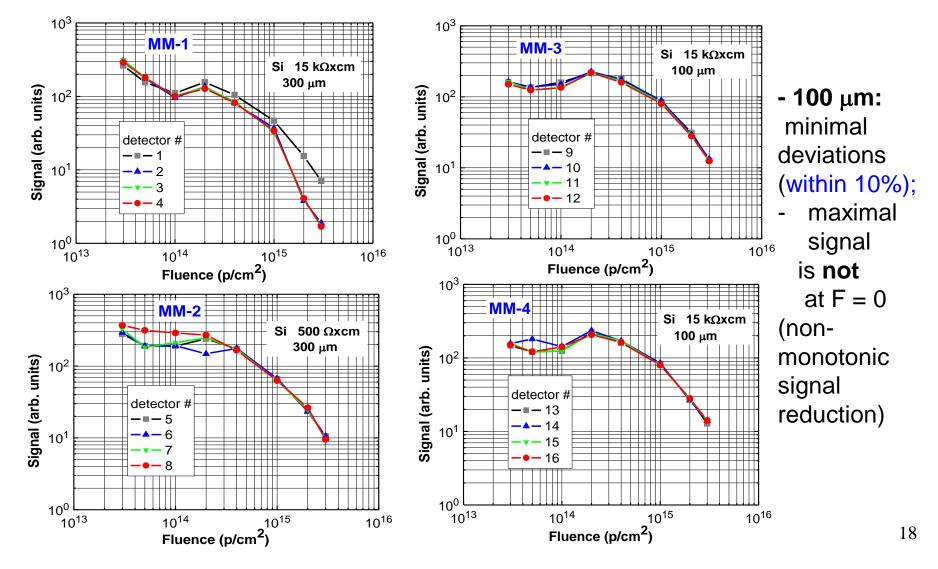
Higher efficiency of thinned detectors is due to two factors:

- 1) E_{mean} is higher,
- 2) Different E(x) distribution

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RadTest 3: statistics of signals

Data from loffe DAQ system; 16 detectors from modules MM1-MM4



Conclusions

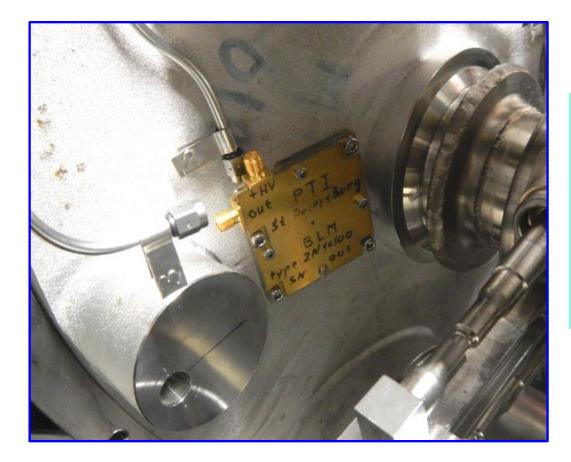
- ✓ The rate of signal degradation at 1.9K is higher than at RT.
- ✓ Si detectors are appropriate for BLM application at 1.9K and irradiation up to $F = 2 \times 10^{15} \text{ p/cm}^2$.
- ✓ Operation in CID mode is advantageous up to $F \sim 2 \times 10^{15} \text{ p/cm}^{2}$.
- Thin (100 mm) detectors give lower rate of signal degradation and minimal deviations of the signal.
- ✓ Not all is clear!
- **V** 4 Gb data are still under treatment

Publications

- C. Kurfürst, et al., Nucl. Instrum. Meth. A 782 (2015) 149.
- E. Verbitskaya, et al., Nucl. Instrum. Meth. A 796 (2015) 118.
- Z. Li, et al., Nucl. Instrum. Meth. A 824 (2016) 476

and references herein.

Most important



2014: First <u>Si BLM module</u> installed on the end of the cold mass of LHe vessel of superconductive coils of the magnets

Thank you for your attention